### The method of least squares

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## Formulation of the problem

Let variable y be a function of another variable x and parameters
 p = p<sub>1</sub>,..., p<sub>n</sub>:

$$y=f(x,\mathbf{p})$$

- Suppose we have a set of N independent measurements of variable y: y = y<sub>1</sub>,..., y<sub>N</sub> with known variances σ<sup>2</sup><sub>1</sub>,..., σ<sup>2</sup><sub>N</sub> taken at N values of x: x = x<sub>1</sub>,..., x<sub>N</sub>
- Goal: construct an estimator for **p**
- Typical applications:
  - Data fitting: have several measurements taken at different times, at different positions etc.
  - Overdetermined systems: problems where the number of unknowns (parameters) is larger than the number of equations (measurements)

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• Construct a function

$$\chi^{2}(\mathbf{p}) = \sum_{i=1}^{N} \frac{(y_{i} - f(x_{i}, \mathbf{p}))^{2}}{\sigma_{i}^{2}}$$
(1)

(this is not the estimator yet)

• Find the minimum of this function w.r.t. p:

$$\frac{\partial \chi^2}{\partial p_i} = 0 \tag{2}$$

(a system of n equations with n unknowns  $\mathbf{p}$ )

- The answer (which is a function of measurements y<sub>i</sub>) is an estimator for parameters **p** 
  - the measurements y<sub>i</sub> do not have to be Gaussian distributed, but they should be unbiased:

$$\langle y_i \rangle = f(x_i, \mathbf{p}_{true})$$

### Special case: linear dependence on parameters

- In general the system of equations (2) is not easy to solve
- Special case:  $f(x, \mathbf{p})$  is a linear function of parameters  $\mathbf{p}$ :

• 
$$f(x_i, \mathbf{p}) = \sum_{j=1} p_j h_j(x_i)$$
, or  $\mathbf{f} = H\mathbf{p}$ , where  $H_{ij} = h_j(x_i)$ 

f doesn't have to be a linear function of x!

• In this case (2) becomes a system of linear equations w.r.t. p

$$\chi^{2}(\mathbf{p}) = \sum_{i=1}^{N} \frac{\left(y_{i} - \sum_{j=1}^{n} p_{j} h_{j}(x_{i})\right)^{2}}{\sigma_{i}^{2}}$$
$$\frac{\partial \chi^{2}}{\partial p_{k}} = -2 \sum_{i=1}^{N} \frac{y_{i} - \sum_{j=1}^{n} p_{j} h_{j}(x_{i})}{\sigma_{i}^{2}} h_{k}(x_{i}) = 0$$
$$\sum_{j=1}^{n} p_{j} \sum_{i=1}^{N} \frac{h_{j}(x_{i})h_{k}(x_{i})}{\sigma_{i}^{2}} = \sum_{i=1}^{N} \frac{y_{i}h_{k}(x_{i})}{\sigma_{i}^{2}}$$

### Correlated measurements

• If  $y_i$  are correlated with the covariance matrix  $V_{ij} = cov(y_i, y_j)$ , then

$$\chi^2 = (\mathbf{y} - \mathbf{f})^T R(\mathbf{y} - \mathbf{f})$$
(3)

where  $R = V^{-1}$ 

• If  $y_i$  are uncorrelated, R is diagonal:

$$R = \begin{pmatrix} 1/\sigma_1^2 & 0 & \dots & 0 \\ 0 & 1/\sigma_2^2 & \dots & 0 \\ \dots & \dots & \dots & \dots \\ 0 & 0 & \dots & 1/\sigma_N^2 \end{pmatrix}$$

and we are back to formula (1)

# Correlated measurements (2)

• Some linear algebra: if  $\frac{\partial}{\partial \mathbf{x}} = \begin{pmatrix} \partial/\partial x_1 \\ \dots \\ \partial/\partial x_n \end{pmatrix}$  then for any constant vector  $\mathbf{v}$  and matrix A:

$$\frac{\partial}{\partial \mathbf{x}}(\mathbf{v}^{\mathsf{T}}\mathbf{x}) = \mathbf{v} \quad \frac{\partial}{\partial \mathbf{x}}(\mathbf{x}^{\mathsf{T}}\mathbf{v}) = \mathbf{v} \quad \frac{\partial}{\partial \mathbf{x}}(\mathbf{x}^{\mathsf{T}}A\mathbf{x}) = A\mathbf{x} + A^{\mathsf{T}}\mathbf{x}$$

• Let's apply it to (3) where  $\mathbf{f} = H\mathbf{p}$ :

$$\chi^{2} = \mathbf{y}^{T} R \mathbf{y} - \mathbf{p}^{T} H^{T} R \mathbf{y} - \mathbf{y}^{T} R H \mathbf{p} + \mathbf{p}^{T} H^{T} R H \mathbf{p}$$
$$\frac{\partial \chi^{2}}{\partial \mathbf{p}} = 0 - H^{T} R \mathbf{y} - (\mathbf{y}^{T} R H)^{T} + (H^{T} R H) \mathbf{p} + (H^{T} R H)^{T} \mathbf{p} = 0$$

$$R^T = R$$
, so  $(H^T R H)\mathbf{p} = H^T R \mathbf{y}$ ,  $\mathbf{p} = (H^T R H)^{-1} H^T R \mathbf{y}$ 

• One can show that the covariance matrix for the estimators  $U_{ij} = \text{cov}(p_i, p_j)$  is calculated as  $U = (H^T R H)^{-1}$ 

### Fit with a constant

- There is only one parameter p and f(x) = p, so  $H = \begin{pmatrix} 1 \\ \dots \\ 1 \end{pmatrix}$
- Eq. (1) reduces to



which is exactly what we had for the estimator of the mean

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## Fit with a straight line

- $f(x) = p_0 + p_1 x$ , linear w.r.t. parameters  $p_0$ ,  $p_1$
- Minimizing  $\chi^2$ , we get a system of two equations:

$$\begin{cases} p_0 \sum_{i=1}^{N} \frac{1}{\sigma_i^2} + p_1 \sum_{i=1}^{N} \frac{x_i}{\sigma_i^2} &= \sum_{i=1}^{N} \frac{y_i}{\sigma_i^2} \\ p_0 \sum_{i=1}^{N} \frac{x_i}{\sigma_i^2} + p_1 \sum_{i=1}^{N} \frac{x_i^2}{\sigma_i^2} &= \sum_{i=1}^{N} \frac{x_i y_i}{\sigma_i^2} \end{cases}$$

• Eq. (4) easily generalizes to an arbitrary polynomial fit

$$f(x, \mathbf{p}) = p_0 + p_1 x + \ldots + p_{n-1} x^{n-1}$$

note that it's still linear w.r.t. parameters

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## Properties of least squared method

- In general, the L.S. method is neither unbiased nor efficient
- If parameter dependence is linear then estimators produced by the method are unbiased
- If measurements are Gaussian distributed then the method is asymptotically efficient (i.e. it is more and more efficient as the number of measurements increases)
  - in this case  $\chi^2$  follows the  $\chi^2$  distribution :)

### Example of least squares polynomial fit

• Which fit should we use? Why?



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### F-test

- Let *n* data points be fitted with two models, 1 and 2, where model 1 is "nested" within model 2
  - model 1 has  $k_1$  parameters, and model 2 has  $k_2$  parameters,  $k_1 < k_2$
  - for any choice of parameters in model 1, the same fit can be achieved by some choice of parameters in model 2
- By construction, model 2 gives a better fit than model 1
  - ▶ the question is, does model 2 give significantly better fit than model 1
- Calucalate the F statistic:

$$F = \frac{\left(\frac{\chi_1^2 - \chi_2^2}{k_2 - k_1}\right)}{\left(\frac{\chi_2^2}{n - k_2 - 1}\right)}$$

 The null hypothesis (model 2 does not provide a significantly better fit than model 1) is rejected if the F value calculated from the data is greater than the critical value of the F-distribution (e.g. corresponding to CL=95%)

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### F-test results for our example

- root will calculate the F probabilities for you
- Transition from 3 to 4 appears to be significant



probability that transition  $k-1 \rightarrow k$  is not significant

## Bayesian Information Criterion

- In general, need to add some term to  $\chi^2$  to penalize increasing the number of fit parameters k
- Bayesian information criterion: pick the model with least  $\chi^2 + k \ln n$ 
  - BIC is asymptotically efficient (if one of the models is correct, the probability to pick it approaches 1 as n → ∞)
  - BIS does not requre the models to be nested





## Effective variance

#### • What to do if both x and y values have errors?

- we have a set of N independent measurements of variable y:
   y = y<sub>1</sub>,..., y<sub>N</sub> with known variances σ<sup>2</sup><sub>y1</sub>,..., σ<sup>2</sup><sub>yN</sub> taken at N values of x: x = x<sub>1</sub>,..., x<sub>N</sub> with known variances σ<sup>2</sup><sub>x1</sub>,..., σ<sup>2</sup><sub>xN</sub>
- The usual approach is what is called "effective variance" method: minimize

$$\chi^{2}(\mathbf{p}) = \sum_{i=1}^{N} \frac{(y_{i} - f(x_{i}, \mathbf{p}))^{2}}{\sigma_{y_{i}}^{2} + (f'(x_{i}, \mathbf{p}))^{2} \sigma_{x_{i}}^{2}}$$
(5)

where 
$$f'(x_i, \mathbf{p}) = \left. \frac{\partial f}{\partial x} \right|_{x=x_i}$$

• note that this ruins the linearity of minimization equations, so it's usually better to avoid it, or find the approximate minimum without x uncertainties and then improve the result by taking  $\sigma_{xi}^2$  into account

### Combining statistical and systematic uncertainties

• Assume we have two measurements  $x_1$  and  $x_2$  of the same quantity x

$$x = x_1 \pm \Delta x_1(stat.) \pm \Delta x_1(syst.)$$
  

$$x = x_2 \pm \Delta x_2(stat.) \pm \Delta x_2(syst.)$$

Let's assume that systematic uncertainties are 100% correlated between the two measurements

- How to combine them?
  - we can assume that both measurements are constructed out of two variables: x = r + s
  - *r* is randomly distributed with variance  $\sigma_r = (\Delta x(stat))^2$
  - s is randomly distributed with variance  $\sigma_s = (\Delta x(syst))^2$
  - $\operatorname{cov}(r_1, r_2) = \operatorname{cov}(r_1, s_1) = \operatorname{cov}(r_1, s_2) = \operatorname{cov}(r_2, s_1) = \operatorname{cov}(r_2, s_2) = 0$

$$\bullet \quad \operatorname{cov}(s_1, s_2) = \sigma_{s1}^2 = \sigma_{s2}^2 = \sigma_s^2$$

# Combining statistical and systematic uncertainties (2)

• Determine covariance matrix of the measurements:

$$\begin{split} \sigma_{x1}^2 &= \left\langle (r_1 + s_1)^2 \right\rangle - \left\langle r_1 + s_1 \right\rangle^2 = \sigma_{r1}^2 + \sigma_s^2 \\ \sigma_{x2}^2 &= \left\langle (r_2 + s_2)^2 \right\rangle - \left\langle r_2 + s_2 \right\rangle^2 = \sigma_{r2}^2 + \sigma_s^2 \\ \operatorname{cov}(x_1, x_2) &= \left\langle (r_1 + s_1)(r_2 + s_2) \right\rangle - \left\langle r_1 + s_1 \right\rangle \left\langle r_2 + s_2 \right\rangle = \sigma_s^2 \end{split}$$

• The covariance matrix looks like follows:

$$V = \left(\begin{array}{cc} \sigma_{r1}^2 + \sigma_s^2 & \sigma_s^2 \\ \sigma_s^2 & \sigma_{r2}^2 + \sigma_s^2 \end{array}\right)$$

The rest can be done using the formula for correlated measurements with  $H = \begin{pmatrix} 1 \\ 1 \end{pmatrix}$ 

 This approach can be extended to any number of correlated / uncorrelated uncertainties

## Binned data

- In many cases we are measuring a random quantity, and we are interested in its p.d.f.
- Suppose we want to determine the mass and the width of the  $\Delta^{++}$  particle, how do we do it?
  - $\blacktriangleright$  reminder:  $\Delta^{++}$  is an unstable baryon with a mass of 1232 MeV decaying into a proton and a  $\pi^+$
- Let's consider two methods:  $\pi p$  scattering and invariant mass measurement

# Measuring the parameters of $\Delta^{++}$ : method 1

#### • We have a $\pi^+$ beam incident on a proton target

- we scan a range of  $\pi$  energies and count the number of scattering events as a function of *E* (the energy of the  $\pi p$  system in its center of mass)
- at each (fixed) beam energy, the number of scattering events  $n_i$  is a random (Poisson distributed) quantity with  $\langle n_i \rangle = \sigma_i^2$
- if  $n_i$  is large then Poisson can be approximated by a Gaussian with mean  $n_i$  and standard deviation  $\sqrt{n_i}$
- we assume that the points follow the Breit-Wigner formula

$$f(E) \sim \frac{(\Gamma/2)^2}{(E-M)^2 + (\Gamma/2)^2}$$

where M and  $\Gamma$  are the resonance mass and width, respectively

- As the result of the experiment, we have a set of points **y** (the number of scattering events with their uncertainties) at fixed values of **x** (C.M.S. energy) which we can fit using the least squares method
  - what is the number of parameters to be determined from the fit?
  - is the parameter dependence linear?

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# Total $p\pi^{\pm}$ cross section (PDG summary)



http://pdg.lbl.gov/2013/hadronic-xsections/rpp2012-pipp\_total.dat

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# Measuring the parameters of $\Delta^{++}$ : method 2

- We are working in the STAR collaboration, studying the d+Au collisions
  - $\blacktriangleright$  we are looking for proton- $\pi^+$  pairs and calculate their invariant masses
  - ► each proton-π<sup>+</sup> pair measurement results in a number with an uncertainty
- How we can use these measurements to determine the  $\Delta^{++}$  mass and width?
  - ▶ we don't have "measured points" in the sense of the previous problem
  - we have "density" of the points which we need to convert to the number of events, so we can get an estimate on the density uncertainty
- What is usually used in this case is called "binning"
  - the result of the binning is a "histogram"

## Unbinned vs binned data



is there another resonance at 1.45 GeV?

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# $p\pi^+$ invariant mass distribution (STAR)



arXiv:0801.0450

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# Optimal histogram binning

- In general, there is no such thing as universally optimal bin size, it is always problem dependent (are there any narrow peaks etc.)
- Scott: optimal bin size *h* can be derived from minimizing the integrated mean squared error of the histogram model

IMSE = 
$$\int_{-\infty}^{+\infty} (f_{\text{binned}}(x) - f(x))^2 dx$$

► IMSE is asymptotically minimized by choosing

$$h = \left[ 6/N \int_{-\infty}^{+\infty} (f'(x))^2 dx \right]^2$$

- for normal distribution,  $h = 3.49\sigma/N^{1/3}$
- What if the probability density is far from normal (but still fairly smooth)?

# Optimal histogram binning (2)

- Freedman-Diaconis rule:  $h = 2 IQR/N^{1/3}$ , where  $IQR=Q_3 - Q_1$ is interquartile range
  - $\blacktriangleright$  for normal distribution,  ${\rm IQR}=1.35\,\sigma$
- Example: N = 1000 standard normal random points (h = 0.29)





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- Bins do not have to be of equal width!
  - ► a popular option is to define bins such that every bin has approximately the same number of entries (≥ 5)
  - a good rule of thumb for the number of such bins:  $2N^{2/5}$

size: 0.020

nean: -0.016 ± 0.047